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INFORMATION DISCLOSURE

STATEMENT

JAN 2 5 2006

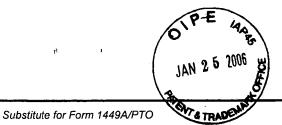
Application #	09/856,358
Confirmation #	6873
Filing Date	May 22, 2001
First Inventor	KEZUKA
Art Unit	1765
Examiner	Umez Eronini, Lynette T.
Docket #	P07223US00/BAS

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

SIR:

TI following	nis IDS is submitted herewith pursuant to 37 CFR. §1.97-1.98 and includes the
🛭 A list	ing of the references on PTO-1449.
⊠ A cop	y of all non-US references which are listed on the PTO-1449 (US refs not required).
	y of a corresponding foreign Search Report which explains the relevance of the ences noted therein.
☐ A sep	arate explanation of relevance.
P	ease note the following particulars concerning the filing of this IDS:
• wi • wi § § • be	s IDS is filed at whichever is the latest of:

3. T	his IDS is filed after a final action or a	llowance, but on/ <u>before</u> payment of the issue fee,
and		he amount of \$180.00 required by 37 CFR.
and	any communication from a foreign particle than three months prior to the C. I hereby state that no item of inforcommunication from a foreign patent my knowledge after making reasonal	rmation in this IDS herewith was cited in a t office in a counterpart foreign application, and, to ble inquiry, was known to any individual e than 3 months prior to the filing of this IDS.
	This IDS does not comply with 37 CFR pursuant to 37 CFR. §1.97(i)	1.97-1.98, and is being filed for placement in the
а. b. c. d.	609; but if for some reason it does not requested to telephone the undersigne Some of the documents may have ma attached to those markings. These documents are not necessarily	n of an abstract is provided from a public source,
 pay		due in connection with this communication or if the missioner is authorized to charge any fee or to Deposit Account No. 12-0555.
Date:	25 January 2006	Respectfully submitted, By: B. Aaron Schulman Registration No.: 31,877
STIT		Fairfax St. • Suite 900 • Alexandria, VA 22314



Customized PTO/SB/08a+b (07-05)

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STATEMENT BY APPLICANT

Sheet <u>1</u> of <u>1</u>

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U.S. PATENT DOCUMENTS				
Exam. Initial*	Document No. Number - Kind	Publ. Date MM-DD-YYYY	Name Patentee or Applicant	Relevance Passages/Figs.
00000	US-3,518,135	06-30-1970	CERNIGLIA ET AL	
0000	US-4,395,304	07-26-1983	KERN ET AL	
	US-5,824,601	10-20-1998	DAO ET AL	"-
W /MA	US-5,571,375	11-05-1996	IZUMI ET AL	
:	US-			
	US-			
	US-			

-	FOREIGN PATENT DOCUMENTS					
Exam. Initial*	Country-Number-Kind	Publ. Date MM-DD-YYYY	Name Patentee or Applicant	Relevance Passages/Figs.	Trans- lation	
/MA/	WO 94/27314	11-24-1994	INTERUNIVERSITAIR ICROELEKTRONICA CENTRUM			
		 				

Exam. Initial*	Include NAME of the author (in CAPS), Title of Article/Item, Date, Page(s), Volume-Issue No., Publisher, City and/or Country where published	Trans- lation
	TAMIS et al; 'Characterisation of oxidation-induced stacking faults in soi structures by a new chemical etching process" January 1992; pgs. A193-A195; vol. 7; Semiconductor science and technology; United Kingdom	

Examiner Signature	/Maki Angadi/	Date Considered	02/04/2008

^{*} Examiner: Initial if considered, whether or not citation is in conformance with MPEP §609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.